



STV160NF03LA

N-CHANNEL 30V - 0.0021Ω - 160A PowerSO-10 STripFET™ POWER MOSFET

TYPE	V _{DSS}	R _{DS(on)}	I _D
STV160NF03LA	30 V	< 0.003 Ω	160 A

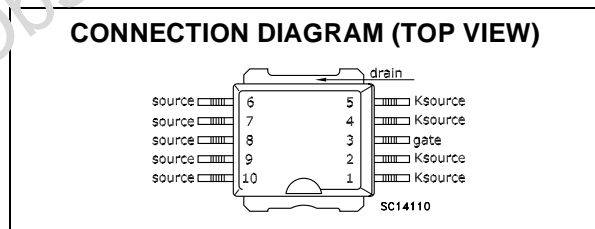
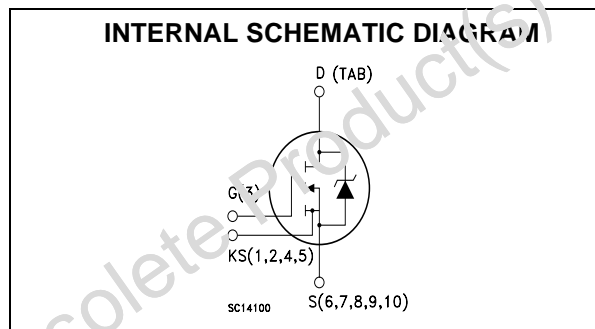
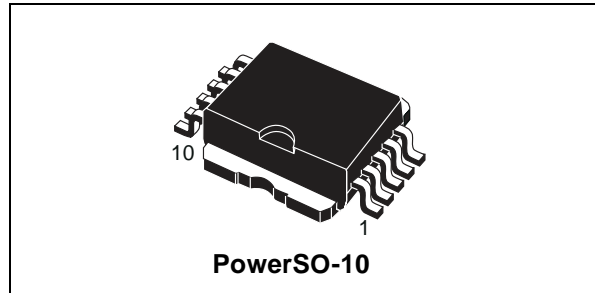
- TYPICAL R_{DS(on)} = 0.0021 Ω
- LOW THRESHOLD DRIVE
- ULTRA LOW ON-RESISTANCE
- ULTRA FAST SWITCHING
- 100% AVALANCHE TESTED
- VERY LOW GATE CHARGE
- LOW PROFILE, VERY LOW PARASITIC INDUCTANCE PowerSO-10 PACKAGE

DESCRIPTION

The **STV160NF03LA** represents the second generation of Application Specific STMicroelectronics well established STripFET™ process based on a very unique strip layout design. The resulting MOSFET shows unrivalled high packing density with ultra low on-resistance and superior switching characteristics. Process simplification also translates into improved manufacturing reproducibility. This device is particularly suitable for high current, low voltage switching application where efficiency is crucial

APPLICATIONS

- BUCK CONVERTERS IN HIGH PERFORMANCE TELECOM AND VRMs DC-DC CONVERTERS



ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source Voltage (V _{GS} = 0)	30	V
V _{DGS}	Drain-gate Voltage (R _{GS} = 20 kΩ)	30	V
V _{GS}	Gate- source Voltage	± 15	V
I _D (**)	Drain Current (continuous) at T _C = 25°C	160	A
I _D	Drain Current (continuous) at T _C = 100°C	113	A
I _{DM} (●)	Drain Current (pulsed)	640	A
P _{TOT}	Total Dissipation at T _C = 25°C	210	W
	Derating Factor	1.4	W/°C
E _{AS} (1)	Single Pulse Avalanche Energy	330	mJ
T _{stg}	Storage Temperature	-65 to 175	°C
T _j	Max. Operating Junction Temperature	175	°C

(●) Pulse width limited by safe operating area
Note: Marking will be STV160NF03AL

(1) V_{DD} = 35V, I_D = 45A, R_G = 22Ω, L = 330μH, Starting T_j = 25°C
(**) Limited only maximum junction temperature allowed by PowerSO-10

STV160NF03LA

THERMAL DATA

Rthj-case	Thermal Resistance Junction-case Max	0.71	°C/W
Rthj-amb	Thermal Resistance Junction-ambient Max	50	°C/W
T _I	Maximum Lead Temperature For Soldering Purpose	300	°C

ELECTRICAL CHARACTERISTICS (TCASE = 25 °C UNLESS OTHERWISE SPECIFIED)

OFF

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown Voltage	I _D = 250 μA, V _{GS} = 0	30			V
I _{DSS}	Zero Gate Voltage Drain Current (V _{GS} = 0)	V _{DS} = Max Rating V _{DS} = Max Rating, T _C = 125 °C			1 10	μA μA
I _{GSS}	Gate-body Leakage Current (V _{DS} = 0)	V _{GS} = ± 15 V			±100	nA

ON (1)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D = 250μA	1			V
R _{DS(on)}	Static Drain-source On Resistance	V _{GS} = 10 V, I _D = 80 A V _{GS} = 10 V, I _D = 45 A V _{GS} = 8 V, I _D = 80 A V _{GS} = 5 V, I _D = 40 A V _{GS} = 10 V, I _D =80 A; T _J = 175 °C V _{GS} = 8 V, I _D =80 A; T _J = 175 °C V _{GS} = 5 V, I _D =40 A; T _J = 175 °C		2.1 2.05 2.2 4.2	3 3 4 7 6.6 8.8 15.4	mΩ mΩ mΩ mΩ mΩ mΩ mΩ
I _{D(on)}	On State Drain Current	V _{DS} > I _{D(on)} × R _{DS(on)} max, V _{GS} = 10V	160			A

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
g _{fs} (1)	Forward Transconductance	V _{DS} > I _{D(on)} × R _{DS(on)} max, I _D = 80 A		210		S
R _g	Gate resistance	V _{DS} = 0 V, f = 1 MHz, V _{GS} = 0		1.1		Ω
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V _{DS} = 25 V, f = 1 MHz, V _{GS} = 0		5350 1700 300		pF pF pF
C _{iss} C _{oss} C _{rss}	Input Capacitance Output Capacitance Reverse Transfer Capacitance	V _{DS} = 0 V, f = 1 MHz, V _{GS} = 0		8200 12400 5200		pF pF pF
L _S	Internal Source Inductance	From the Lead End (6mm from Package Body) to the Die Center		3		nH
L _D	Internal Drain Inductance		Not Available on Surface Mounting Package			

ELECTRICAL CHARACTERISTICS (CONTINUED)

SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on Delay Time	$V_{DD} = 15\text{ V}$, $I_D = 80\text{ A}$ $R_G = 4.7\Omega$, $V_{GS} = 10\text{ V}$ (see test circuit, Figure 3)		30		ns
t_r	Rise Time			380		ns
Q_g	Total Gate Charge	$V_{DD} = 24\text{ V}$, $I_D = 160\text{ A}$, $V_{GS} = 10\text{ V}$		123	160	nC
Q_{gs}	Gate-Source Charge			21		nC
Q_{gd}	Gate-Drain Charge			40		nC

SWITCHING OFF

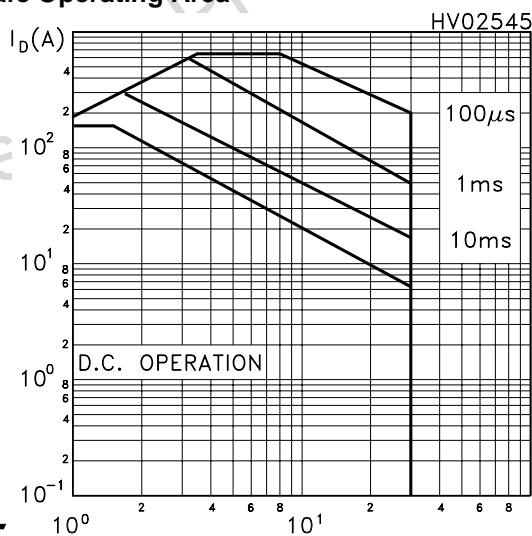
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$t_{d(off)}$	Turn-off-Delay Time	$V_{DD} = 15\text{ V}$, $I_D = 80\text{ A}$, $R_G = 4.7\Omega$, $V_{GS} = 10\text{ V}$ (see test circuit, Figure 5)		100		ns
t_f	Fall Time			150		ns
$t_{d(off)}$	Turn-off Delay Time	$V_{clamp} = 24\text{ V}$, $I_D = 40\text{ A}$ $R_G = 4.7\Omega$, $V_{GS} = 10\text{ V}$		95		ns
$t_r(V_{off})$	Off-voltage Rise Time			35		ns
t_f	Fall Time			75		ns
t_c	Cross-over Time			110		ns

SOURCE DRAIN DIODE

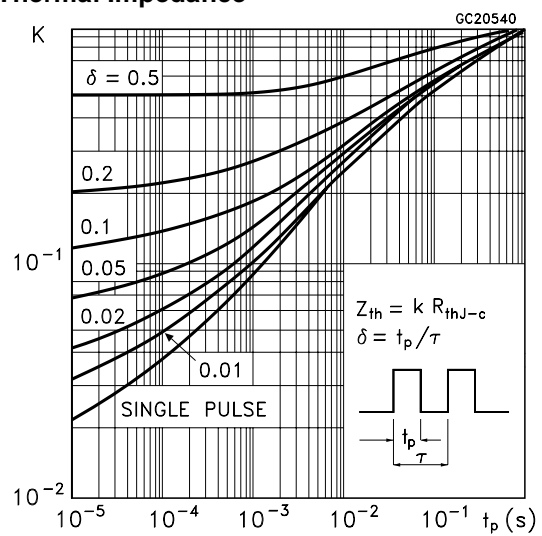
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
I_{SD}	Source-drain Current				160	A
$I_{SDM(1)}$	Source-drain Current (pulsed)				640	A
$V_{SD(2)}$	Forward On Voltage	$I_{SD} = 160\text{ A}$, $V_{GS} = 0$			1.5	V
t_{rr}	Reverse Recovery Time	$I_{SD} = 160\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$, $V_{DD} = 15\text{ V}$, $T_j = 25^\circ\text{C}$ (see test circuit, Figure 5)		80		ns
Q_{rr}	Reverse Recovery Charge			180		nC
I_{RRM}	Reverse Recovery Current			4.5		A

Note: 1. Pulsed: Pulse duration = 300 μs , duty cycle 1.5 %.
2. Pulse width limited by safe operating area.

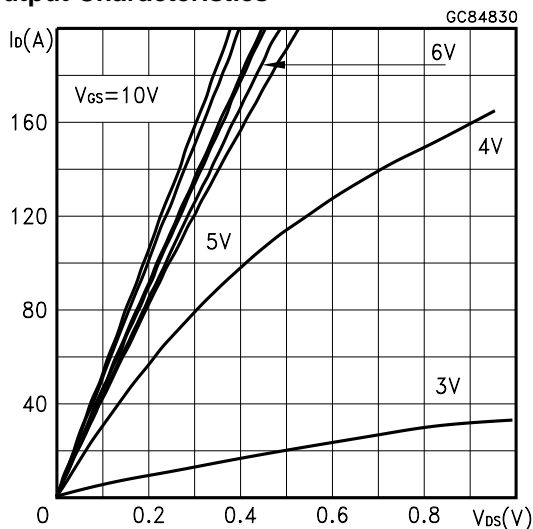
Safe Operating Area



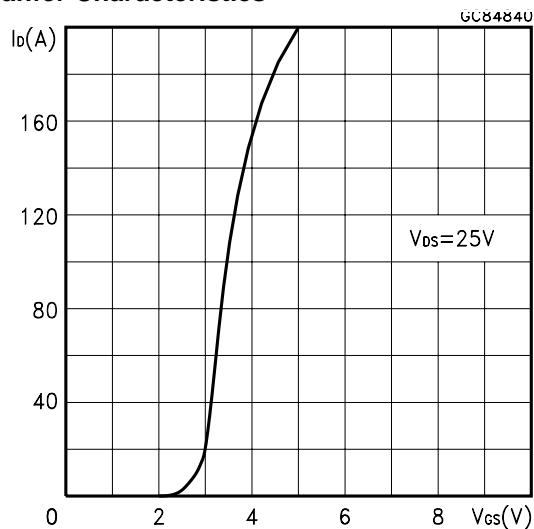
Thermal Impedance



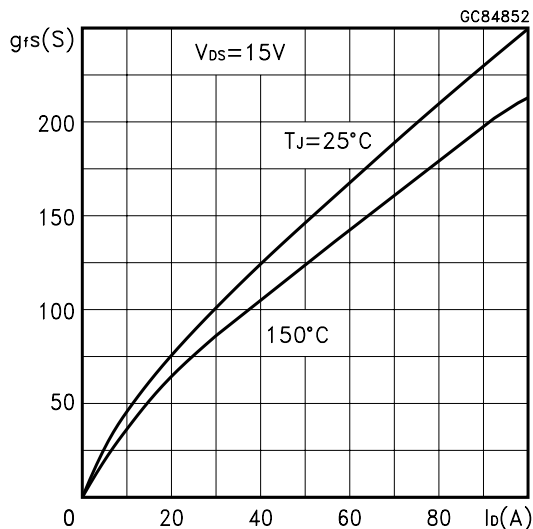
Output Characteristics



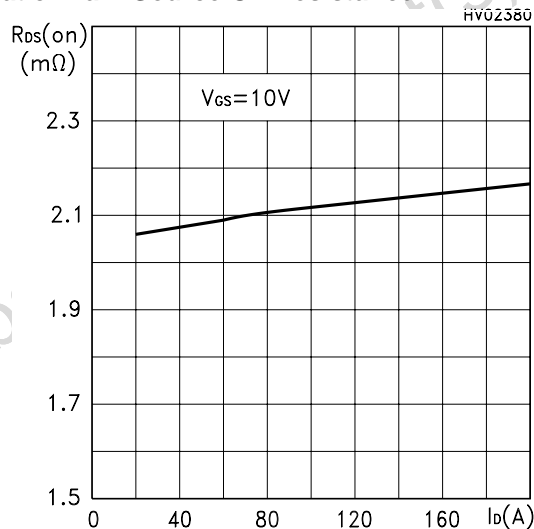
Transfer Characteristics



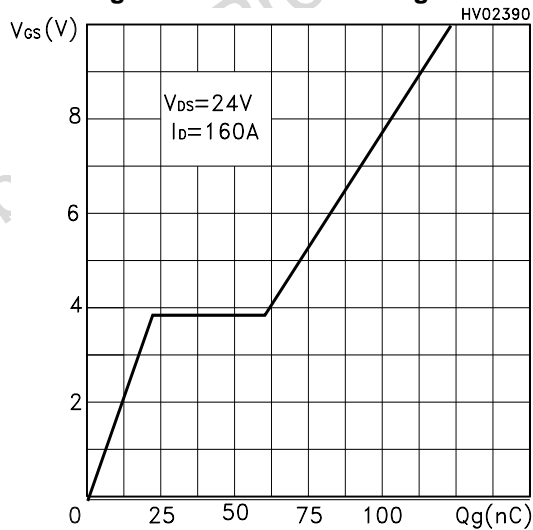
Transconductance



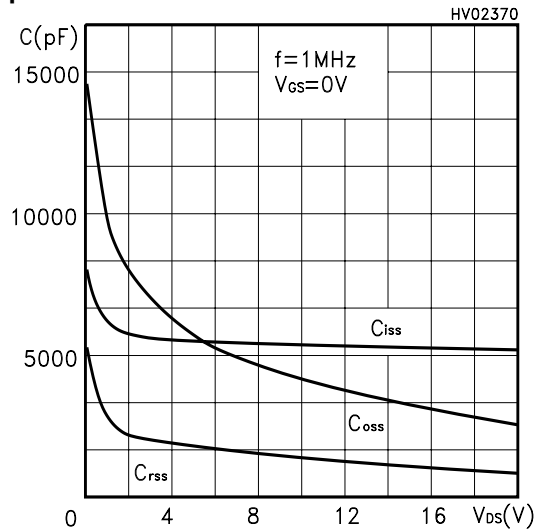
Static Drain-Source On Resistance



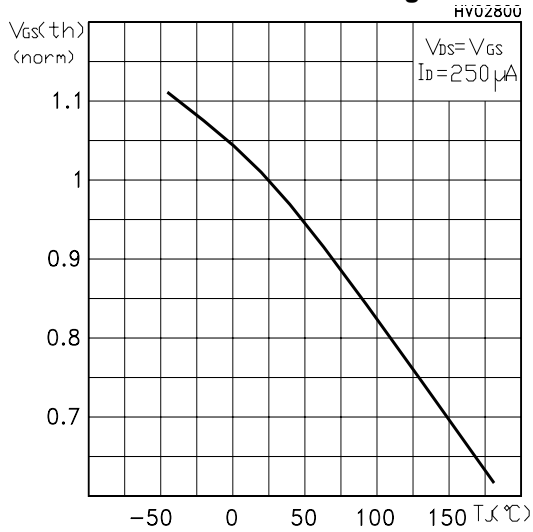
Gate Charge vs Gate-source Voltage



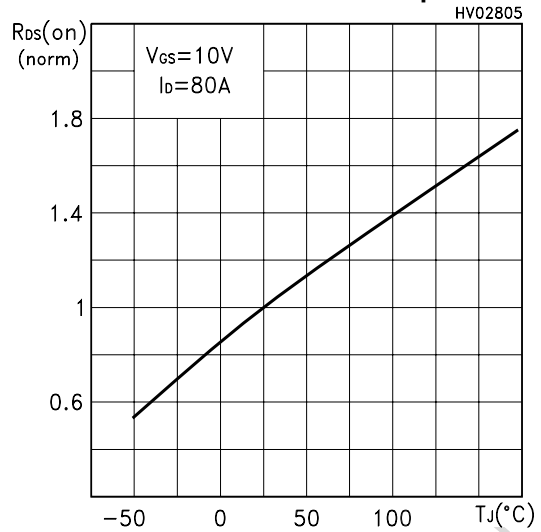
Capacitance Variations



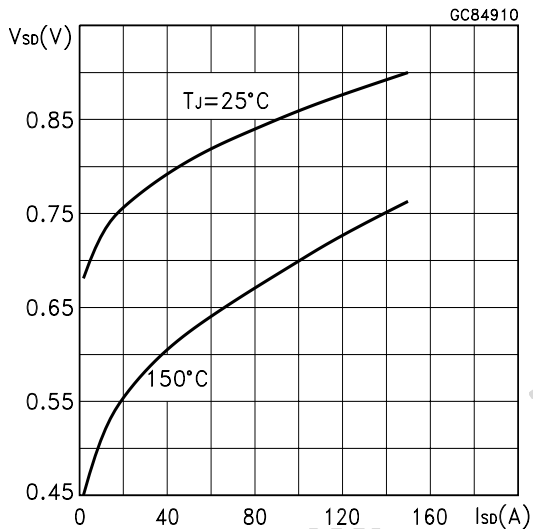
Normalized Gate Threshold Voltage vs Temp.



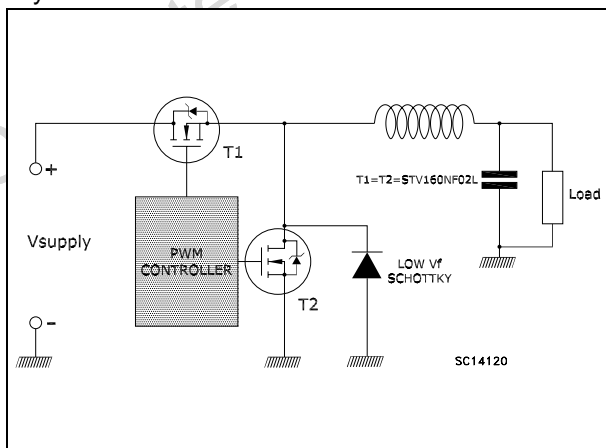
Normalized On Resistance vs Temperature



Source-drain Diode Forward Characteristics



Basic Schematic For Motherboard VRM With Synchronous Rectification



Basic Schematic Mosfets Switch Used In Secondary Side Of a Froward Convert

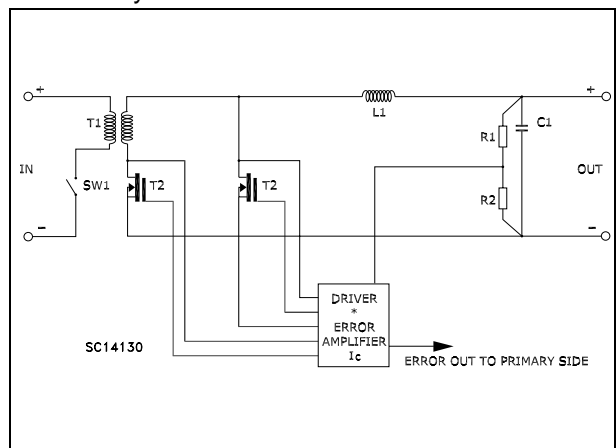


Fig. 1: Unclamped Inductive Load Test Circuit

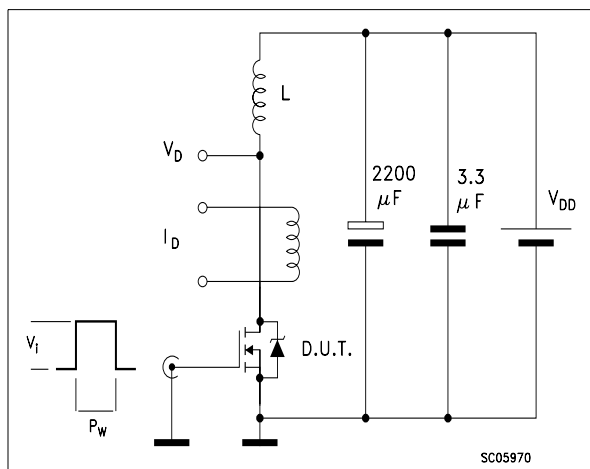


Fig. 2: Unclamped Inductive Waveform

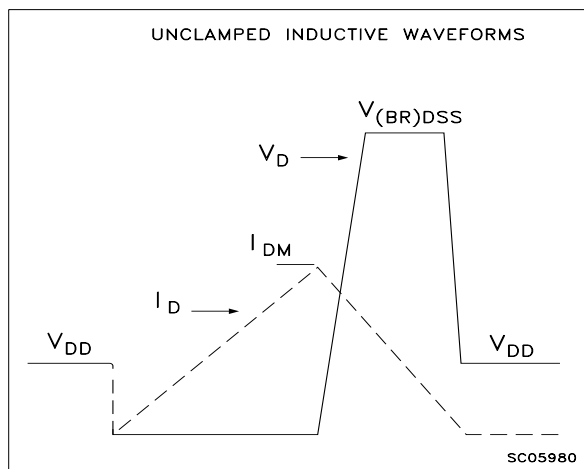


Fig. 3: Switching Times Test Circuit For Resistive Load

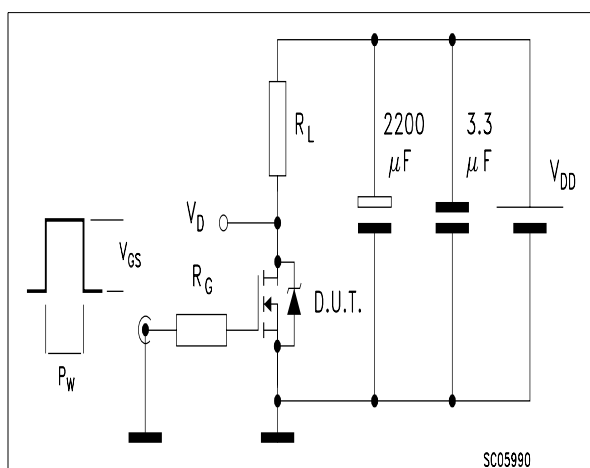


Fig. 4: Gate Charge test Circuit

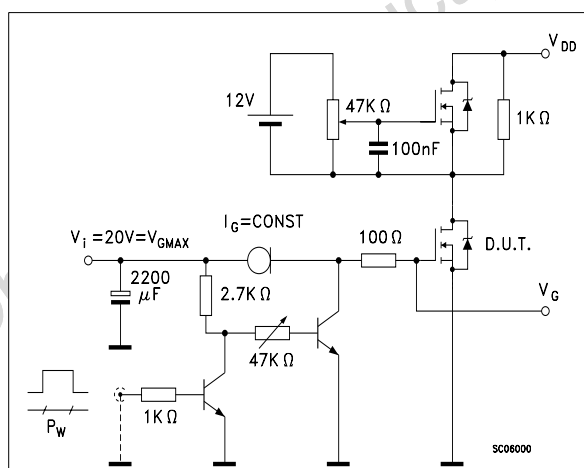
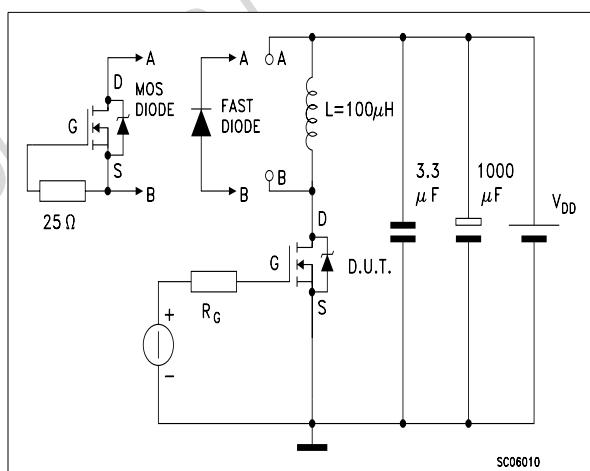
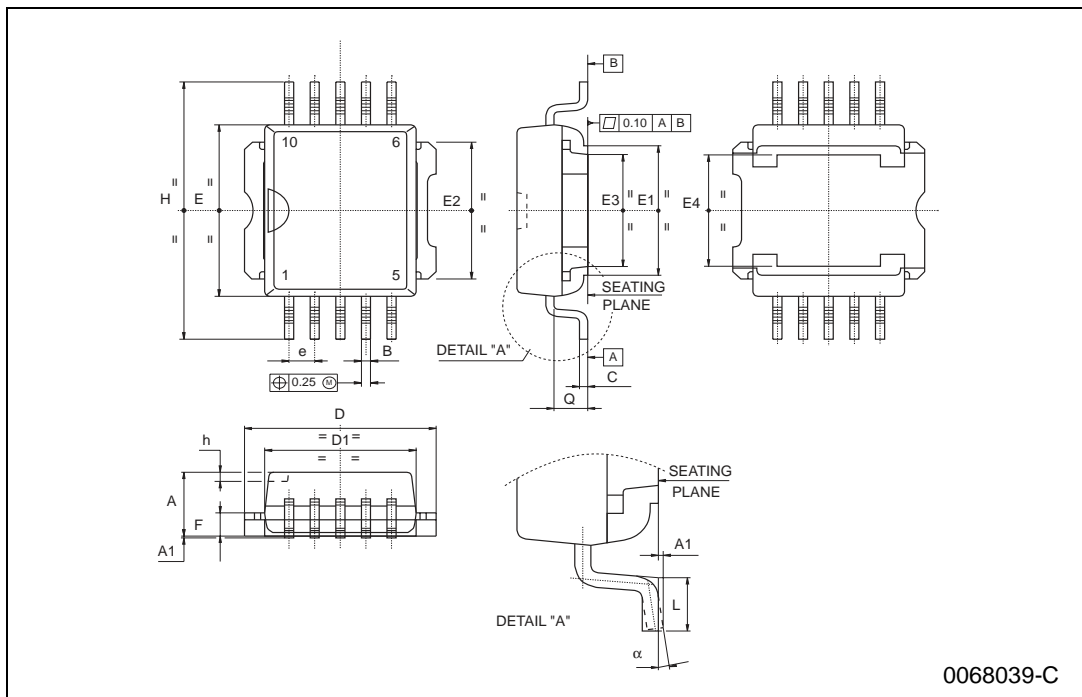


Fig. 5: Test Circuit For Inductive Load Switching And Diode Recovery Times



PowerSO-10 MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A	3.35		3.65	0.132		0.144
A1	0.00		0.10	0.000		0.004
B	0.40		0.60	0.016		0.024
C	0.35		0.55	0.013		0.022
D	9.40		9.60	0.370		0.378
D1	7.40		7.60	0.291		0.300
e		1.27			0.050	
E	9.30		9.50	0.366		0.374
E1	7.20		7.40	0.283		0.291
E2	7.20		7.60	0.283		0.300
E3	6.10		6.35	0.240		0.250
E4	5.90		6.10	0.232		0.240
F	1.25		1.35	0.049		0.053
h		0.50			0.002	
H	13.80		14.40	0.543		0.567
L	1.20		1.80	0.047		0.071
q		1.70			0.067	
α	0°		8°			



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